Power MOSFET

30 V, 10.5 A, N-Channel, SO-8

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Optimized for 5 V, 12 V Gate Drives
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- DC-DC Converters
- Printers

MAXIMUM RATINGS (T_J = 25°C unless otherwise stated)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V_{DSS}	30	V
Gate-to-Source Voltage	Gate-to-Source Voltage			±20	V
Continuous Drain	Steady	T _A = 25°C	I _D	8.5	Α
Current R _{θJA} (Note 1)	State T _A = 70°C			6.8	
Power Dissipation $R_{\theta JA}$ (Note 1)	Steady State	T _A = 25°C	P _D	1.28	W
Continuous Drain	Steady	T _A = 25°C	I _D	7.1	Α
Current R _{θJA} (Note 2)	State	T _A = 70°C		5.7	
Power Dissipation $R_{\theta JA}$ (Note 2)		T _A = 25°C	P _D	0.88	W
Continuous Drain			I _D	10.5	Α
Current $R_{\theta JA}$, $t \le 10 s$ (Note 1)	State	T _A = 70°C		8.4	
Power Dissipation $R_{\theta JA}$, $t \le 10 \text{ s(Note 1)}$	Steady State	T _A = 25°C	P _D	1.95	W
Pulsed Drain Current	Pulsed Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \mu s$			127	Α
Operating Junction and Storage Temperature		T _J , T _{stg}	–55 to 150	°C	
Source Current (Body Diode)			I _S	2.4	Α
Single Pulse Drain-to–Source Avalanche Energy (T_J = 25°C, V_{DD} = 30 V, V_{GS} = 10 V, I_L = 8 A_{pk} , L = 1.0 mH, R_G = 25 Ω)		E _{AS}	32	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Ambient - Steady State (Note 1)	$R_{\theta JA}$	97.4	°C/W
$Junction-to-Ambient - t \le 10 s (Note 1)$	$R_{\theta JA}$	64	
Junction-to-Foot (Drain)	$R_{\theta JF}$	25.9	
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	142.4	

- 1. Surfacemounted on FR4 board using 1 in sq pad size, 1 oz Cu.
- 2. Surfacemounted on FR4 board using the minimum recommended pad size.

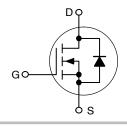


ON Semiconductor®

http://onsemi.com

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
30 V	11 mΩ @ 10 V	10.5 A
30 V	15 mΩ @ 4.5 V	10.5 A

N-Channel



1 SO-8 CASE 751 STYLE 12

MARKING DIAGRAM/ PIN ASSIGNMENT

Source B Drain
Source B Drain
Source B Drain
Source B Drain
Top View

4917N = Device Code A = Assembly Location Y = Year

WW = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]				
NTMS4917NR2G	SO-8 (Pb-Free)	2500/Tape & Reel				

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J				16		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V, V _{DS} = 30 V	T _J = 25°C			1.0	μΑ
		v _{GS} = 0 v, v _{DS} = 30 v	T _J = 125°C			10	
Gate-to-Source Leakage Current	I _{GSS}	V _{DS} = 0 V, V _{GS} =	±20 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_D = 2$	250 μΑ	1.0	1.7	2.5	V
Negative Threshold Temperature Coefficient	V _{GS(TH)} /T _J				5		mV/°C
Drain-to-Source On Resistance	R _{DS(on)}	V _{GS} = 10 V, I _D =	: 11 A		8.25	11	mΩ
		V _{GS} = 4.5 V, I _D	= 9 A		11.25	15	7
Forward Transconductance	9FS	V _{DS} = 1.5 V, I _D =	7.5 A		19		S
CHARGES, CAPACITANCES AND GA	ATE RESISTAN	ICE	<u> </u>				
Input Capacitance	C _{iss}				1054		pF
Output Capacitance	C _{oss}	V _{GS} = 0 V, f = 1.0 MHz	V _{DS} = 25 V		325		
Reverse Transfer Capacitance	C _{rss}				165		
Total Gate Charge	Q _{G(TOT)}				15.6		nC
Threshold Gate Charge	Q _{G(TH)}				2.6		1
Gate-to-Source Charge	Q _{GS}	$V_{GS} = 4.5 \text{ V}, V_{DS} = 15^{\circ}$	V, I _D = 7.5 A		4.2		1
Gate-to-Drain Charge	Q_{GD}				7		1
Total Gate Charge	Q _{G(TOT)}	V _{GS} = 10 V, V _{DS} = 15 V	V, I _D = 7.5 A		29		nC
SWITCHING CHARACTERISTICS (No		I					
Turn-On Delay Time	t _{d(on)}				8.5		ns
Rise Time	t _r	V 10 V V	- 15 V		6.3		1
Turn-Off Delay Time	t _{d(off)}	$V_{GS} = 10 \text{ V, } V_{DS} = I_D = 1.0 \text{ A, } R_G = I_{CS} = I_$	6.0 Ω		27		1
Fall Time	t _f				12		1
DRAIN-SOURCE DIODE CHARACTE			l		1		1
Forward Diode Voltage	V_{SD}		T _J = 25°C		0.75	1.0	V
		$V_{GS} = 0 \text{ V}, I_{S} = 2.0 \text{ A}$	T _J = 125°C		0.58		
Reverse Recovery Time	t _{RR}				28		ns
Charge Time	t _a	$V_{GS} = 0 \text{ V, } d_{IS}/d_t = 100 \text{ A/}\mu\text{s,}$ $I_S = 2.0 \text{ A}$			12.2		1
Discharge Time	t _b				15.7		1
Reverse Recovery Charge	Q _{RR}				20		nC
PACKAGE PARASITIC VALUES	1				1		<u>I</u>
Source Inductance	L _S				0.66		nH
Drain Inductance	L _D	T _A = 25°C			0.2		1
Gate Inductance	L _G				1.5		1
Gate Resistance	R _G				0.70		Ω

Pulse Test: pulse width = 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

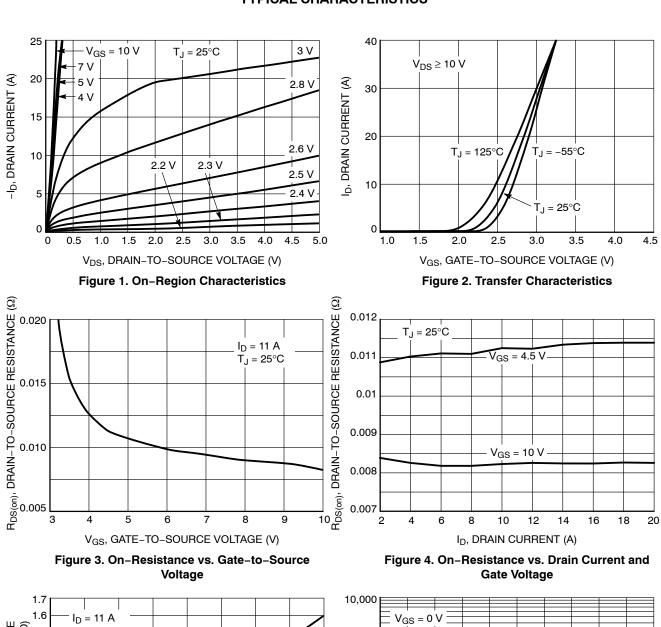


Figure 5. On–Resistance Variation with Temperature

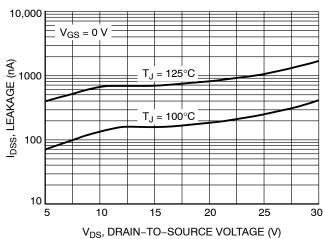


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

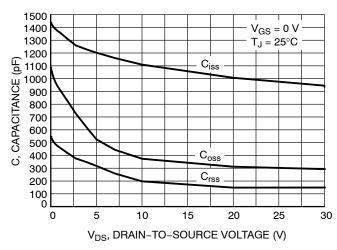


Figure 7. Capacitance Variation

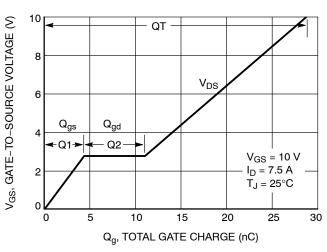


Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

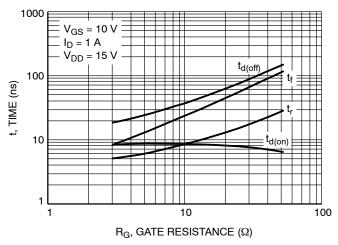


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

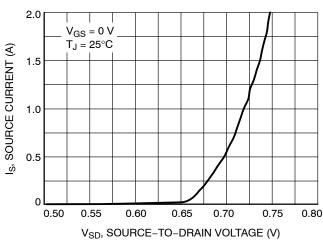


Figure 10. Diode Forward Voltage vs. Current

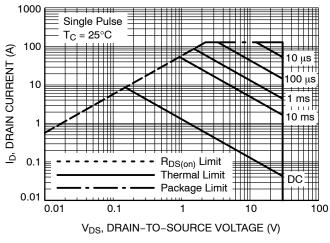


Figure 11. Maximum Rated Forward Biased Safe Operating Area

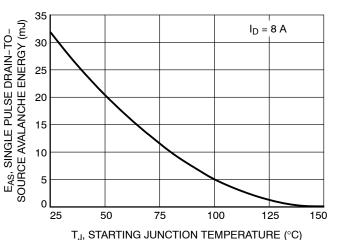
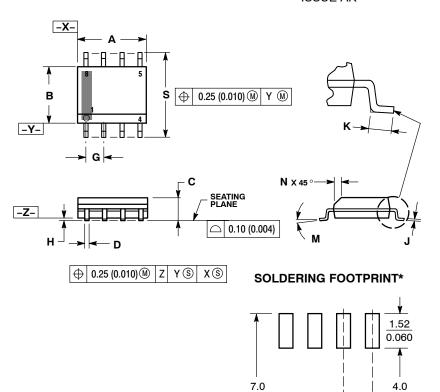


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07 **ISSUE AK**



0.275

0.6

0.024

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION A AND B DO NOT INCLUDE
 MOLD PROTRUSION.
 MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- PER SIDE.

 DIMENSION D DOES NOT INCLUDE DAMBAR
- PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT
- MAXIMUM MATERIAL CONDITION. 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.80	5.00	0.189	0.197		
В	3.80	4.00	0.150	0.157		
С	1.35	1.75	0.053	0.069		
D	0.33	0.51	0.013	0.020		
G	1.27	1.27 BSC		0 BSC		
Н	0.10	0.25	0.004	0.010		
J	0.19	0.25	0.007	0.010		
K	0.40	1.27	0.016	0.050		
М	0 °	8 °	0 °	8 °		
N	0.25	0.50	0.010	0.020		
S	5.80	6.20	0.228	0.244		

STYLE 12:

- SOURCE
 - SOURCE SOURCE 2. 3.
 - GATE
 - 5. DRAIN
 - DRAIN
 - DRAIN DRAIN

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

0.155

1.270

0.050

SCALE 6:1

mm

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